



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Inventors: Osamu ICHIKAWA Art Unit: 2829
Appln. No.: 10/647,506 Exr.: J. Hollington
Filed: August 26, 2003
For: SEMICONDUCTOR INTEGRATED CIRCUIT AND MEMORY TEST
METHOD

PRELIMINARY AMENDMENT

Honorable Commissioner of
Patents and Trademarks
Washington, DC 20231

Sir:

Please amend the above application as follows:

02/02/2005 FFANAEIA 00000084 10647506

01 FC:1201	400.00 OP
02 FC:1202	100.00 OP